IN THE ABSTRACT OF THE DISCLOSURE:

Please delete the present Abstract of the Disclosure and replace it with the following new Abstract of the Disclosure:

--A system and method for determining the stray radiation condition of a projection system, is presented herein. The invention includes providing a detector with a detector aperture coincident with the image plane of the projection system, measuring a reference parameter in accordance with the projection beam intensity, measuring a stray radiation parameter of an image of an isolated feature and calculating a coefficient representative of the stray radiation condition of the projection system based on the measured stray radiation parameter and the reference parameter. The extent of the detector aperture fits within the extent of a notional shape, which is defined by first scaling down the shape of the feature and subsequently displacing each line element constituting the edge of the scaled down shape, parallel to itself, over a distance of at least λ/NA in a direction perpendicular to that line element.--